

Device Reliability Prediction

Case 1 - Black Box Estimates (50% Stress, Temp. = 40 Deg. C, No Device burn-in)

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Unit: LMZ14201

Manufacturer: Texas Instruments Inc.

<i>Device Type</i>	<i>Qty</i>	<i>Failure Rate</i>	<i>Quality Factor</i>	<i>Total Device Failure Rate</i>
Capacitor, Fixed, Ceramic	3	1	1	3
Inductor, Power Filter	1	19	1	19
IC, Analog	1	1.8	1	1.8
<i>Total FIT Rate:</i>				23.8
<i>Equivalent MTBF (hrs):</i>				42,016,807